

		U.S. F	PATENT DOCUMENTS		
Examiner Initials*	Γ	U.S. Patent Document	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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			FOREIC	ON PATENT DOCUMENTS		
Examiner Initials*	Cite No. 1	Office	Number Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
77		JP	2000-049222	Hitachi Ltd.	02-18-2000	
11		US	5,981,356	Integrated Device Technology, Inc.	11-09-1999	
	- 10					

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No. 1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
П		English Bibliography and Abstract of JP 2000-049222 (noted above).		

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Examiner	1100	1.4	Date Considered	04-16-02
Signature		MAL		04-16-02

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